

**INSULATED GATE BIPOLAR TRANSISTOR WITH
ULTRAFAST SOFT RECOVERY DIODE**

Features

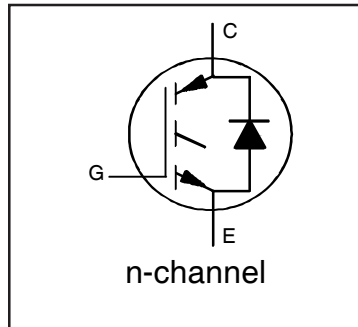
- Low $V_{CE(ON)}$ Trench IGBT Technology
- Low switching losses
- Maximum Junction temperature 175 °C
- 5 μ S short circuit SOA
- Square RBSOA
- 100% of the parts tested for 4X rated current (I_{LM})^①
- Positive $V_{CE(ON)}$ Temperature Coefficient
- Soft Recovery Co-Pak Diode
- Tight parameter distribution
- Lead-Free, RoHS Compliant
- Automotive Qualified *

Benefits

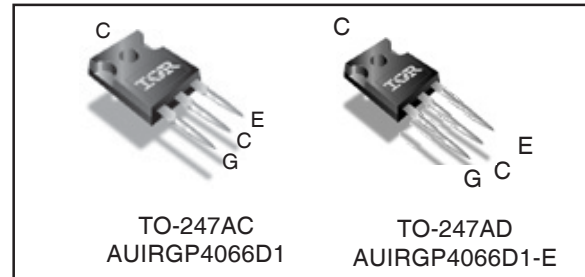
- High Efficiency in a wide range of applications
- Suitable for a wide range of switching frequencies due to Low $V_{CE(ON)}$ and Low Switching losses
- Rugged transient Performance for increased reliability
- Excellent Current sharing in parallel operation
- Low EMI

Ordering Information

Base part number	Package Type	Standard Pack		Complete Part Number
		Form	Quantity	
AUIRGP4066D1	TO-247AC	Tube	25	AUIRGP4066D1
AUIRGP4066D1-E	TO-247AD	Tube	25	AUIRGP4066D1-E



$V_{CES} = 600V$
$I_{C(Nominal)} = 75A$
$t_{SC} \geq 5\mu s, T_{J(max)} = 175^{\circ}C$
$V_{CE(on)} \text{ typ.} = 1.70V$



G	C	E
Gate	Collector	Emitter

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (T_A) is 25°C, unless otherwise specified.

	Parameter	Max.	Units	
V_{CES}	Collector-to-Emitter Voltage	600	V	
$I_C @ T_C = 25^{\circ}C$	Continuous Collector Current	140 ^⑤	A	
$I_C @ T_C = 100^{\circ}C$	Continuous Collector Current	90		
$I_{NOMINAL}$	Nominal Current	75		
I_{CM}	Pulse Collector Current $V_{GE} = 15V$	225		
I_{LM}	Clamped Inductive Load Current $V_{GE} = 20V$ ^①	300		
$I_{F NOMINAL}$	Diode Nominal Current ^②	75 ^⑤		
I_{FM}	Diode Maximum Forward Current ^②	300		
V_{GE}	Continuous Gate-to-Emitter Voltage	± 20		V
	Transient Gate-to-Emitter Voltage	± 30		
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	454		W
$P_D @ T_C = 100^{\circ}C$	Maximum Power Dissipation	227		
T_J	Operating Junction and Storage Temperature Range	-55 to +175	°C	
	Soldering Temperature, for 10 sec.	300 (0.063 in. (1.6mm) from case)		
	Mounting Torque, 6-32 or M3 Screw	10 lbf-in (1.1 N-m)		

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units
$R_{\theta JC}$ (IGBT)	Thermal Resistance Junction-to-Case-(each IGBT) ^④	—	—	0.33	°C/W
$R_{\theta JC}$ (Diode)	Thermal Resistance Junction-to-Case-(each Diode) ^④	—	—	0.53	
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink (flat, greased surface)	—	0.24	—	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient (typical socket mount)	—	40	—	

*Qualification standards can be found at <http://www.irf.com/>

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage	600	—	—	V	$V_{GE} = 0V, I_C = 200\mu\text{A}$ ④
$\Delta V_{(BR)CES}/\Delta T_J$	Temperature Coeff. of Breakdown Voltage	—	0.30	—	V/°C	$V_{GE} = 0V, I_C = 15\text{mA}$ (25°C-175°C)
$V_{CE(on)}$	Collector-to-Emitter Saturation Voltage	—	1.70	2.1	V	$I_C = 75\text{A}, V_{GE} = 15V, T_J = 25^\circ\text{C}$ ②
		—	2.0	—		$I_C = 75\text{A}, V_{GE} = 15V, T_J = 150^\circ\text{C}$ ②
		—	2.1	—		$I_C = 75\text{A}, V_{GE} = 15V, T_J = 175^\circ\text{C}$ ②
$V_{GE(th)}$	Gate Threshold Voltage	4.0	—	6.5	V	$V_{CE} = V_{GE}, I_C = 2.1\text{mA}$
$\Delta V_{GE(th)}/\Delta T_J$	Threshold Voltage temp. coefficient	—	-13	—	mV/°C	$V_{CE} = V_{GE}, I_C = 20\text{mA}$ (25°C - 175°C)
g_{fe}	Forward Transconductance	—	50	—	S	$V_{CE} = 50V, I_C = 75\text{A}, \text{PW} = 25\mu\text{s}$
I_{CES}	Collector-to-Emitter Leakage Current	—	3.0	200	μA	$V_{GE} = 0V, V_{CE} = 600V$
		—	10	—	mA	$V_{GE} = 0V, V_{CE} = 600V, T_J = 175^\circ\text{C}$
V_{FM}	Diode Forward Voltage Drop	—	1.60	1.77	V	$I_F = 75\text{A}$
		—	1.54	—		$I_F = 75\text{A}, T_J = 175^\circ\text{C}$
I_{GES}	Gate-to-Emitter Leakage Current	—	—	± 100	nA	$V_{GE} = \pm 20V$

Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
Q_g	Total Gate Charge (turn-on)	—	150	225	nC	$I_C = 75\text{A}$
Q_{ge}	Gate-to-Emitter Charge (turn-on)	—	40	60		$V_{GE} = 15V$
Q_{gc}	Gate-to-Collector Charge (turn-on)	—	60	90		$V_{CC} = 400V$
E_{on}	Turn-On Switching Loss	—	4240	5190	μJ	$I_C = 75\text{A}, V_{CC} = 400V, V_{GE} = 15V$
E_{off}	Turn-Off Switching Loss	—	2170	3060		$R_G = 10\Omega, L = 100\mu\text{H}, T_J = 25^\circ\text{C}$
E_{total}	Total Switching Loss	—	6410	8250		Energy losses include diode & diode reverse recovery
$t_{d(on)}$	Turn-On delay time	—	50	70	ns	$I_C = 75\text{A}, V_{CC} = 400V, V_{GE} = 15V$
t_r	Rise time	—	80	100		$R_G = 10\Omega, L = 100\mu\text{H}$
$t_{d(off)}$	Turn-Off delay time	—	200	230		$T_J = 25^\circ\text{C}$
t_f	Fall time	—	60	80		
E_{on}	Turn-On Switching Loss	—	6210	—		μJ
E_{off}	Turn-Off Switching Loss	—	2815	—	$R_G = 10\Omega, L = 100\mu\text{H}, T_J = 175^\circ\text{C}$	
E_{total}	Total Switching Loss	—	9025	—	Energy losses include diode & diode reverse recovery	
$t_{d(on)}$	Turn-On delay time	—	45	—	ns	$I_C = 75\text{A}, V_{CC} = 400V, V_{GE} = 15V$
t_r	Rise time	—	70	—		$R_G = 10\Omega, L = 100\mu\text{H}$
$t_{d(off)}$	Turn-Off delay time	—	240	—		$T_J = 175^\circ\text{C}$
t_f	Fall time	—	80	—		
C_{ies}	Input Capacitance	—	4470	—		pF
C_{oes}	Output Capacitance	—	350	—	$V_{CC} = 30V$	
C_{res}	Reverse Transfer Capacitance	—	140	—	$f = 1.0\text{MHz}$	
RBSOA	Reverse Bias Safe Operating Area	FULL SQUARE				$T_J = 175^\circ\text{C}, I_C = 300\text{A}$ $V_{CC} = 480V, V_p \leq 600V$ $R_G = 10\Omega, V_{GE} = +20V \text{ to } 0V$
SCSOA	Short Circuit Safe Operating Area	5	—	—	μs	$V_{CC} = 400V, V_p \leq 600V$ $R_G = 10\Omega, V_{GE} = +15V \text{ to } 0V$
E_{rec}	Reverse Recovery Energy of the Diode	—	680	—	μJ	$T_J = 175^\circ\text{C}$
t_{rr}	Diode Reverse Recovery Time	—	240	—	ns	$V_{CC} = 400V, I_F = 75\text{A}$
I_{rr}	Peak Reverse Recovery Current	—	50	—	A	$V_{GE} = 15V, R_G = 10\Omega, L = 100\mu\text{H}$

Notes:

- ① $V_{CC} = 80\% (V_{CES}), V_{GE} = 20V, L = 100\mu\text{H}, R_G = 50\Omega$, tested in production $I_{LM} \leq 400\text{A}$.
- ② Pulse width limited by max. junction temperature.
- ③ Refer to AN-1086 for guidelines for measuring $V_{(BR)CES}$ safely.
- ④ R_{θ} is measured at T_J of approximately 90°C .
- ⑤ Calculated continuous current based on maximum allowable junction temperature. Package IGBT current limit is 120A. Package diode current limit is 120A. Note that current limitations arising from heating of the device leads may occur.